

F-6971

Form PTO-1449 (Rev. 7-80) 42-44P (P-49)		U.S. Department of Commerce Patent and Trademark Office		Atty. Docket No.: F-6971		Serial No.: 09/852,111	
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				Applicant: Seichi HAYASHI, et al.			
				Filing Date: May 9, 2001		Group: 2882	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
TRANSLATION KEY: * English Abstract. ^a Concise statement of relevance provided in foreign search report. ^c Concise statement of relevance provided in specification. ^b Concise statement of relevance provided in IDS. ^p Relevant portion of reference translated. ^o English abstract only - copy of reference in pct search.							
OTHER INFORMATION DISCLOSURE CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)							
hks		1997 - X-ray Reflectometer for the Diagnostics of Thin Films During Growth, U. Niggemeier, K. Lischka, W. M. Plotz and V. Holy, Journal of Applied Crystallography, Volume 30, Pages 905-908					
EXAMINER Hoon K. Song				DATE CONSIDERED 2/13/05			
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